

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1-10. (Canceled)

11. (Currently Amended) An electronic device testing apparatus, for conducting a test of electronic devices prior to molding ~~at least~~ by pressing input/output terminals of said electronic devices against a contact portions of a test head ~~while said electronic devices are loaded on a strip format,; wherein,~~

said test head has a plurality of contact groups composed of a set of said contact portions,
said electronic device testing apparatus comprises comprising at least one moving means capable of simultaneously gripping a plurality of said strip formats ~~arranged along the planar direction of said strip formats~~ at a loading position of pre-test electronic devices, while conveying said gripped strip formats to said contact portions without reloading said electronic devices from said strip formats, and while pressing input/output terminals of said electronic devices against said contact portions at the same time said electronic devices are being loaded on said strip formats,

said each strip format gripped by said moving means corresponds to said each contact group, and

the sum of said contact portions which compose said a plurality of contact groups
matches with the simultaneously measured number limited in said electronic device testing
apparatus.

12.(Previously Presented) The electronic device testing apparatus as set forth in claim 11, wherein said moving means is capable of freely selecting the gripping number within the number able to be gripped.

13. (Previously Presented) The electronic device testing apparatus as set forth in claim 11, wherein said one moving means is capable of freely selecting the gripping number being independent from other moving means.

14. (Previously Presented) The electronic device testing apparatus as set forth in claim 11, wherein said any two or more moving means among said plurality of moving means have a substantially overlapping operation range on a contact group as a set of said contact portions.

15. (Canceled)

16. (Previously Presented) The electronic device testing apparatus as set forth in claim 11, wherein each of said moving means grips and moves said strip format from said contact portions to a loading position of post-test electronic devices.

17. (Previously Presented) The electronic device testing apparatus as set forth in claim 11, wherein a sum of the numbers of contact portions in said test head is 2^n ("n" is a natural number).

18. (Previously Presented) The electronic device testing apparatus as set forth in claim 17, wherein n=5 or n=6.

19-26. (Canceled)